

# Product Change Notification - JAON-04UCYV212

**Date:** 06 Dec 2016  
**Product Category:** Memory  
**Notification subject:** CCB 2745 Initial Notice: Qualification of 35.8K process technology for selected products of the 25xx128 and 25xx256 device families available in 8L TSSOP package.  
**Notification text:** **PCN Status:**  
Initial notification

**Microchip Parts Affected:**

Please open the attachments found in the attachments field below labeled as PCN\_#\_Affected\_CPN.

NOTE: For your convenience Microchip includes identical files in two formats (.pdf and .xls).

**Description of Change:**

Qualification of 35.8K process technology for selected products of the 25xx128 and 25xx256 device families available in 8L TSSOP package.

**Pre Change:**

Available in 160K wafer technology fabricated at Microchip fabrication sites FAB2 and FAB4 (Tempe, AZ and Gresham, OR, USA) using 8 inch wafers

**Post Change:**

Available in 160K wafer technology fabricated at Microchip fabrication sites FAB2 and FAB4 (Tempe, AZ and Gresham, OR, USA) using 8 inch wafers or available in 35.8K wafer technology fabricated at FAB 5 (Colorado Springs, CO, USA) using 6 inch wafers

**Pre and Post Change Summary:**

	Pre Change	Post Change	
<b>Wafer Technology</b>	160K wafer technology	160K wafer technology	35.8K wafer technology
<b>Fabrication Location</b>	Microchip Fabrication Sites FAB 2 and FAB4 (Tempe, AZ and Gresham, OR, USA)	Microchip Fabrication Sites FAB 2 and FAB4 (Tempe, AZ and Gresham, OR, USA)	FAB 5 (Colorado Springs, CO USA)
<b>Wafer Diameter</b>	8 inches (200 mm)	8 inches (200 mm)	6 inches (150 mm)
<b>Quality certification</b>	ISO/TS16949	ISO/TS16949	ISO9001/TS16949

**Impacts to Data Sheet:**

None

**Change Impact:**

None

**Reason for Change:**

To improve manufacturability by qualifying an additional fabrication site.

**Change Implementation Status:**

In Progress

**Estimated Qualification Completion Date:**

January 2017

NOTE:

1. In order to receive products only fabricated with the current 160K process please use the revised part number identified with RVA added to the end of the part number (see example below).

Standard Part Number: 25xx128x-x/xx or 25xx256x-x/xx

Revised Part Number (160K only): 25xx128x-x/xxRVA or 25xx256x-xx/xxRVA

2. Please be advised the qualification completion times may be extended because of unforeseen business conditions however implementation will not occur until after qualification has completed and a final PCN has been issued. The final PCN will include the qualification report and estimated first ship date.

**Time Table Summary:**

	December 2016					->	January 2017			
	48	49	50	51	52		01	02	03	04
Workweek										
Initial PCN Issue Date		X								
Qual Report Availability							X			
Final PCN Issue Date							X			

**Method to Identify Change:**

Traceability code

**Qualification Plan:**

Please open the attachments included with this PCN labeled as PCN\_#\_Qual Plan.

**Revision History:**

**December 6, 2016:** Issued initial notification.

The change described in this PCN does not alter Microchip's current regulatory compliance regarding the material content of the applicable products.

**Attachment(s):**

[PCN\\_JAON-04UCYV212\\_Qual Plan.pdf](#)

[PCN\\_JAON-04UCYV212\\_Affected CPN.pdf](#)

[PCN\\_JAON-04UCYV212\\_Affected CPN.xls](#)

Please contact your local [Microchip sales office](#) with questions or concerns regarding this notification.

**Terms and Conditions:**

If you wish to change your product/process change notification (PCN) profile please log on to our website at

To opt out of future offer or information emails (other than product change notification emails), click here to go to [microchipDIRECT](#) and login, then click on the "My account" link, click on "Update profile" and un-check the box that states "Future offers or information about Microchip's products or services."

JAON-04UCYV212 - CCB 2745 Initial Notice: Qualification of 35.8K process technology for selected products of the 25xx128 and 25xx256 device families available in 8L TSSOP package.

Affected Catalog Part Numbers (CPN)

PCN_JAON-04UCYV212
CATALOG_PART_NBR
25AA256-I/ST
25AA256T-I/ST
25LC256-E/ST
25LC256-I/ST
25LC256T-E/ST
25LC256T-I/ST
25AA128-I/ST
25AA128T-I/ST
25LC128-E/ST
25LC128-I/ST
25LC128T-E/ST
25LC128T-I/ST



**MICROCHIP**

# **QUALIFICATION PLAN**

**PCN #: JAON-04UCYV212**

**Date**

**September 07, 2016**

**Qualification of 35.8K process technology for selected products of the 25xx128 and 25xx256 device families available in 8L TSSOP package.**

**Distribution:**

Surasit P.	F. Chen
Rangsun K.	O. Baltazar
Mitchell R.	S. Iliev
Chalermpon P.	H. Caballero
Wichai K.	G. Perzanowski
Chaweng W.	

Microchip Technology (Thailand) Co., Ltd.  
14 Moo 1 T. Wangtakien A. Muangchacherngsao,  
Chacherngsao, Thailand, 24000  
Tel. (6638) 857119-45, 857311-19 ext. 1231  
Fax (6638) 857149-50

**Purpose:** \_\_\_\_\_ Qualification of 35.8K process technology for selected products of the 25xx128 and 25xx256 device families available in 8L TSSOP package.

**MP code:** \_\_\_\_\_ 358A24C5X/358A27C5X/358A2TC5X/358A2YC5X

**Part No.:** \_\_\_\_\_ 25LC256/25AA256/25LC256T/25AA256T

**BD No:** \_\_\_\_\_ BDE003951-01

**CCB No.:** \_\_\_\_\_ 2745

**Package:**

**Type** \_\_\_\_\_ 8L TSSOP

**Width or Size** \_\_\_\_\_ 4.4 mm

**Die thickness** \_\_\_\_\_ 11 mils

**Die size** \_\_\_\_\_ 57.1x69.5 mils

**Leadframe:**

**Material** \_\_\_\_\_ C7025/stamped

**Plating** \_\_\_\_\_ Ag spot plated

**Part Number** \_\_\_\_\_ 10100821

**Surface treatment** \_\_\_\_\_ No

**Solder Plating:**

**Material** \_\_\_\_\_ Pure matte tin

**Wire:**

**Material** \_\_\_\_\_ Au wire

**Die Attach Film:**

**Part Number** \_\_\_\_\_ 2200D

**Conductive** \_\_\_\_\_ YES

**Mold Compound:**

**Type/Supplier** \_\_\_\_\_ EME-G600V

Test Name	Conditions	Reliability Stress Read Point	Pre & Post Reliability Stress Test Temperature	Sample Size	Min. Qty of Spares per Lot (should be properly marked)	Qty of Lots	Total Units	Fail Accept Qty	Est. Dur. Days	Special Instructions
		-40°C to +125°C datasheet operating range (E Temp)	-40°C to +125°C datasheet operating range (E Temp)							
Wire Bond Pull - WBP	Mil. Std. 883-2011			5	0	1	5	0 fails after TC	5	30 bonds from a min. 5 devices.
Wire Bond Shear - WBS	CDF-AEC-Q100-001			5	0	1	5	0	5	30 bonds from a min. 5 devices.
HTSL (High Temp Storage Life)	+175°C	500 hrs	+25°C, +85°C, +125°C	45	5	1	50	0	10	Spares should be properly identified.
Preconditioning - Required for surface mount devices	+150°C Bake for 24 hours, moisture loading requirements per MSL level + 3X reflow at peak reflow temperature per Jedec-STD-020D for package type. MSL-1 @ 260°C		+25°C	231	15	3	738	0	15	Spares should be properly identified. 77 parts from each lot to be used for HAST, Autoclave, Temp Cycle test.
HAST	+130°C/85% RH for 96 hours or 110°C/85%RH for 264 hours	96 hrs	+25°C, +85°C, +125°C,	77	5	3	246	0	10	Spares should be properly identified. Use the parts which have gone through Pre-conditioning.
Unbiased HAST	+130°C/85% RH for 96 hrs or +110°C/85% RH for 264 hrs	96 hrs or 264 hrs	+25°C	77	5	3	246	0	10	Spares should be properly identified. Use the parts which have gone through Pre-conditioning.
Temp Cycle	-65°C to +150°C. 3 gram force WBP on 5 devices from 1 lot, test following Temp Cycle stress.	500 cycles	+85°C, +125°C,	77	5	3	246	0	15	Spares should be properly identified. Use the parts which have gone through Pre-conditioning.